

**Search Notes****Application/Control No.**

10/659,567

**Examiner**

Erin M. File

**Applicant(s)/Patent under Reexamination**

EGNOR ET AL.

**Art Unit**

2611

**SEARCHED**

Class	Subclass	Date	Examiner
375	262	4/10/2007	EMF
375	340	4/10/2007	EMF
375	341	4/10/2007	EMF
714	786	4/10/2007	EMF
714	794	4/10/2007	EMF
714	795	4/10/2007	EMF

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST US PAT, USPGPUB, EPO, JPO DERNENT, IBM (text search only—see search history printout)	4/10/2007	EMF
IEEE Advanced Keyword Search--See Search History Printout	4/10/2007	EMF

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
PBPUB Text Search Only--See Search Printout History	4/10/2007	EMF	